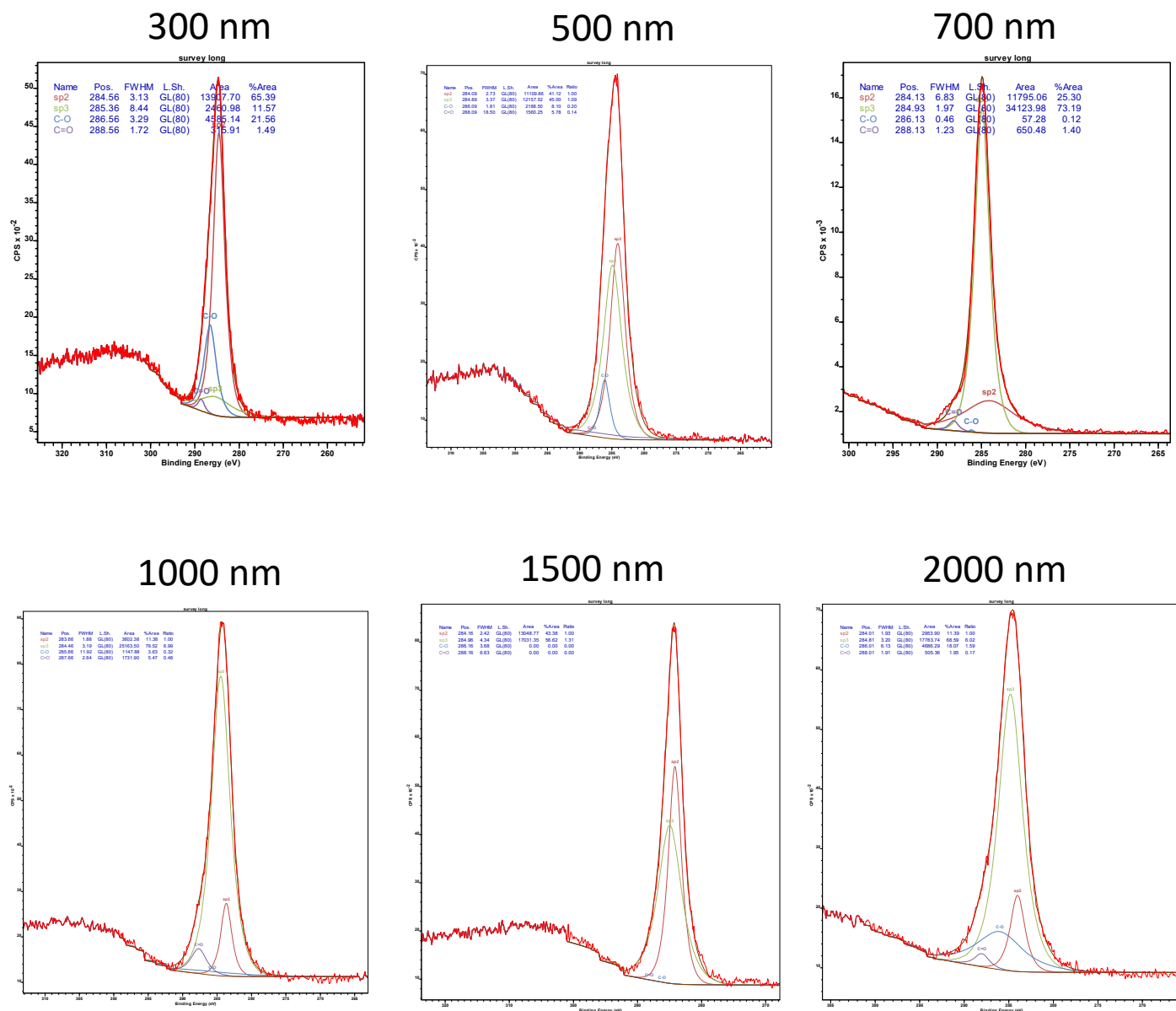


SI 1. XPS C1s Peak deconvolution for the reference, O₂ plasma treated sample and the thin layers from 10-100 nm a-C:H film thickness.



SI 2. XPS C1s Peak deconvolution for the PA6 samples coated with thick a-C:H layers (300-2000 nm).